


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/526,492	EDER ET AL.	
	Examiner	Art Unit	
	Richard Chan	2618	

SEARCHED			
Class	Subclass	Date	Examiner
381	317	9/7/2006	RC
381	312	9/7/2006	RC
455	130	9/7/2006	RC
455	227	9/7/2006	RC
375	316	9/7/2006	RC

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR